

Automated area and coverage optimization of minimal latency checkers

Azad, Siavoosh Payandeh; Niazmand, Behrad; Apneet Kaur; Raik, Jaan; Jervan, Gert; Hollstein, Thomas 2017 22nd IEEE European Test Symposium (ETS 2017), Limassol, Cyprus, 22 – 26 May 2017 : proceedings 2017 / p. 7-8 : ill <https://doi.org/10.1109/ETS.2017.7968211>

Energy-efficient multi-fragment Markov model guided online model-based testing for MPSoC

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From online fault detection to fault management in network-on-chips : a ground-up approach

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Modeling for multi-view interference analysis of design aspects in MPSoC designs

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Multi-fragment Markov model guided online test generation for MPSoC

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Multi-view modeling for MPSoC design aspects [Online resource]

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